



US00D838609S

(12) **United States Design Patent** (10) **Patent No.:** **US D838,609 S**  
**Kim** (45) **Date of Patent:** **\*\* Jan. 22, 2019**

(54) **APPARATUS FOR DETECTING PARTICLE ON TEST FILM**

(71) Applicant: **JEDEX INC.**, Yongin-si, Gyeonggi-do (KR)

(72) Inventor: **Jin Ho Kim**, Suwon-si (KR)

(73) Assignee: **JEDEX INC.**, Yongin-si (KR)

(\*\*) Term: **15 Years**

(21) Appl. No.: **29/617,261**

(22) Filed: **Sep. 13, 2017**

(30) **Foreign Application Priority Data**

Aug. 2, 2017 (KR) ..... 30-2017-0035752

(51) **LOC (11) Cl.** ..... **10-04**

(52) **U.S. Cl.**  
USPC ..... **D10/46; D10/75; D10/81; D24/216**

(58) **Field of Classification Search**  
USPC .... **D10/46, 75, 81; D24/216, 232, 233, 234; 356/237.1, 237.2, 237.3, 237.4, 237.5, 356/237.6, 239.7, 239.8**

CPC ..... **G01N 1/04; G01N 1/20; G01N 15/02; G01N 15/0205; G01N 21/8803; G01N 2001/028**

See application file for complete search history.

(56) **References Cited**

U.S. PATENT DOCUMENTS

9,599,844 B2 \* 3/2017 Kudo ..... G02F 1/1309  
9,983,596 B2 \* 5/2018 Neander ..... G05D 7/0676

\* cited by examiner

*Primary Examiner* — Antoine Duval Davis

(74) *Attorney, Agent, or Firm* — Novick, Kim & Lee, PLLC; Jae Youn Kim

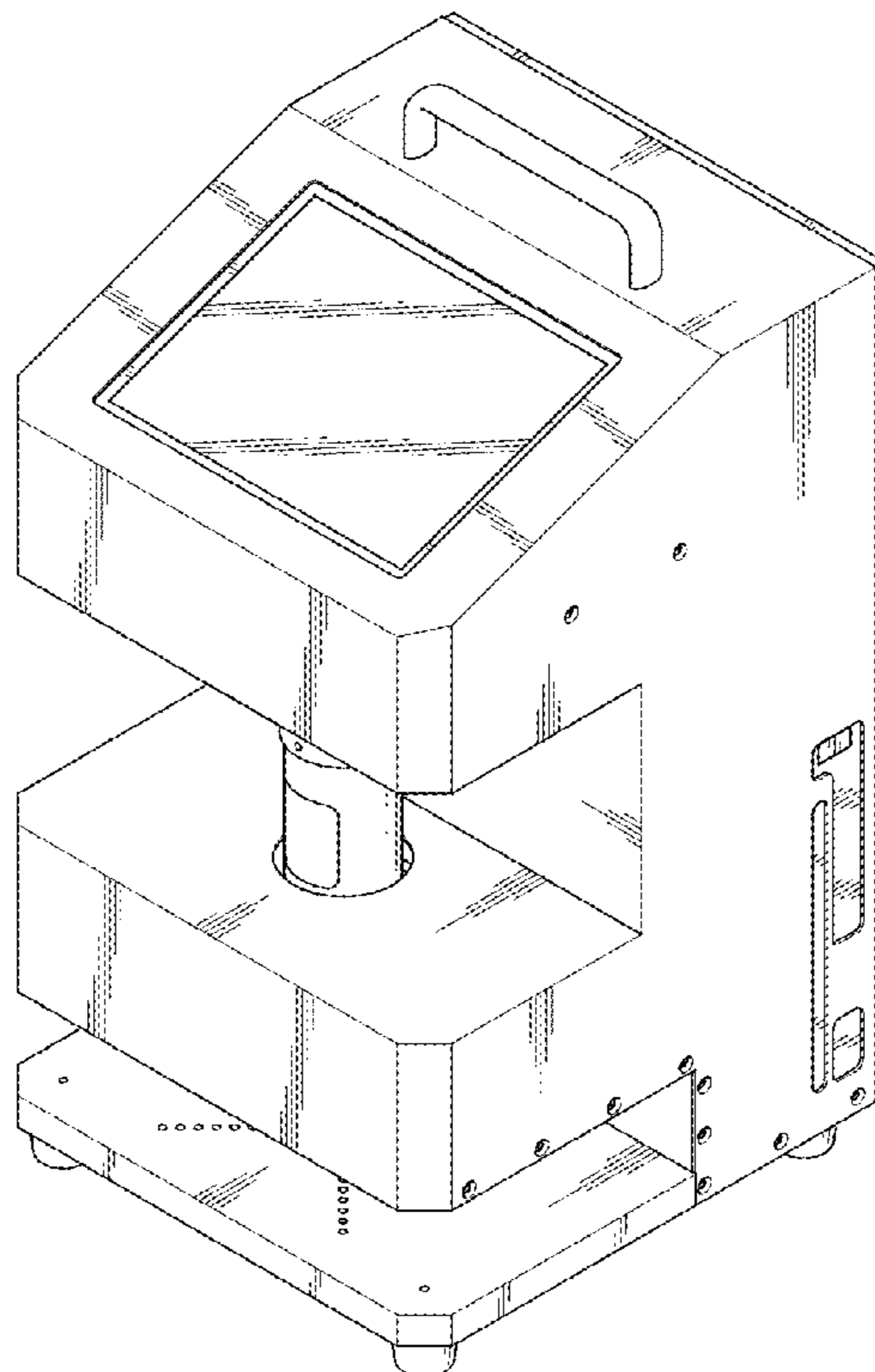
(57) **CLAIM**

I claim, the ornamental design for an apparatus for detecting particles on test film, as shown and described.

**DESCRIPTION**

FIG. 1 is a perspective view of an apparatus for detecting particles on test film, showing my new design; FIG. 2 is a front elevational view thereof; FIG. 3 is a rear elevational view thereof; FIG. 4 is a left side elevational view thereof; FIG. 5 is a right side elevational view thereof; FIG. 6 is a top plan view thereof; and, FIG. 7 is a bottom plan view thereof.

**1 Claim, 7 Drawing Sheets**



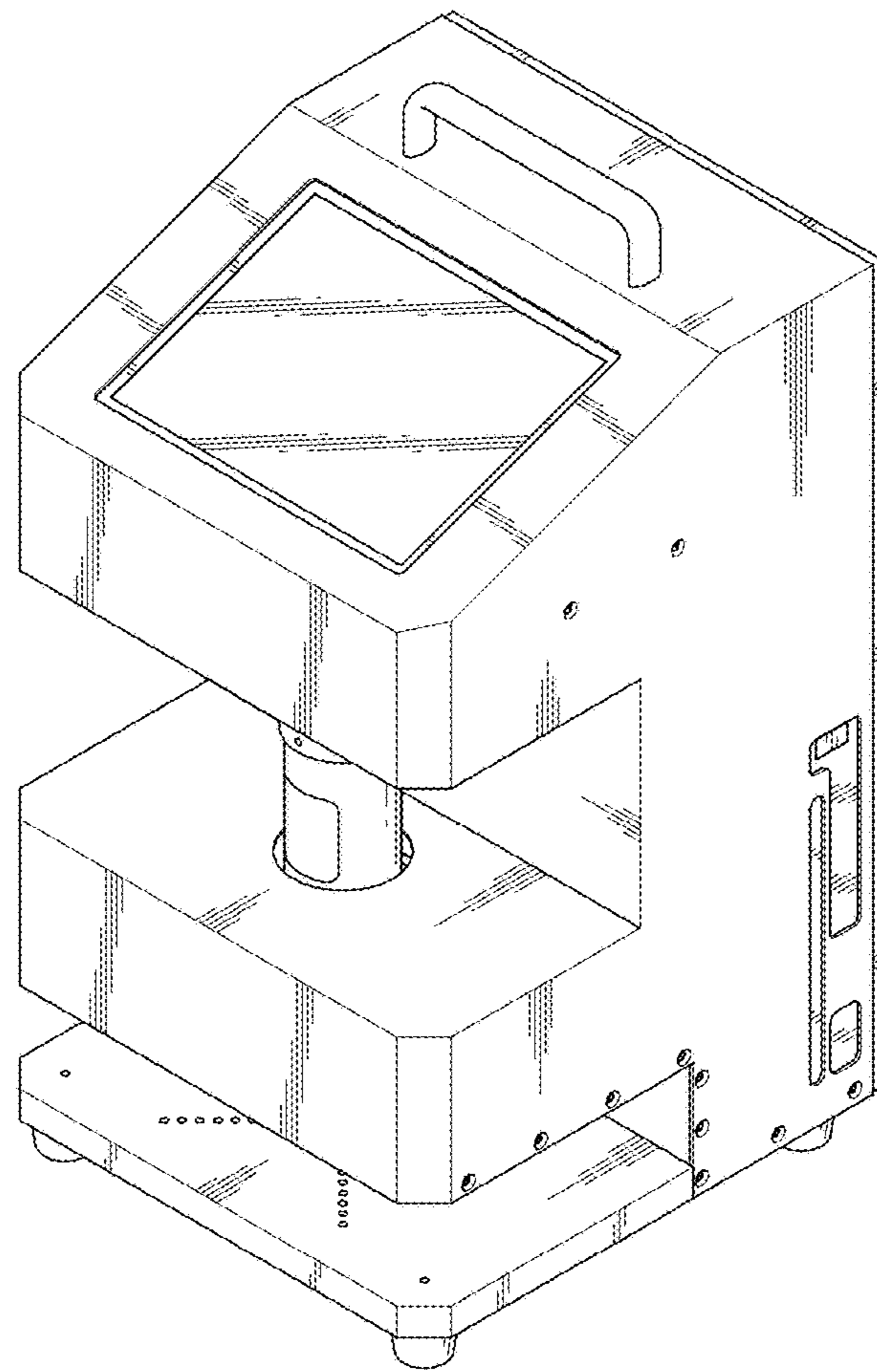


FIG. 1

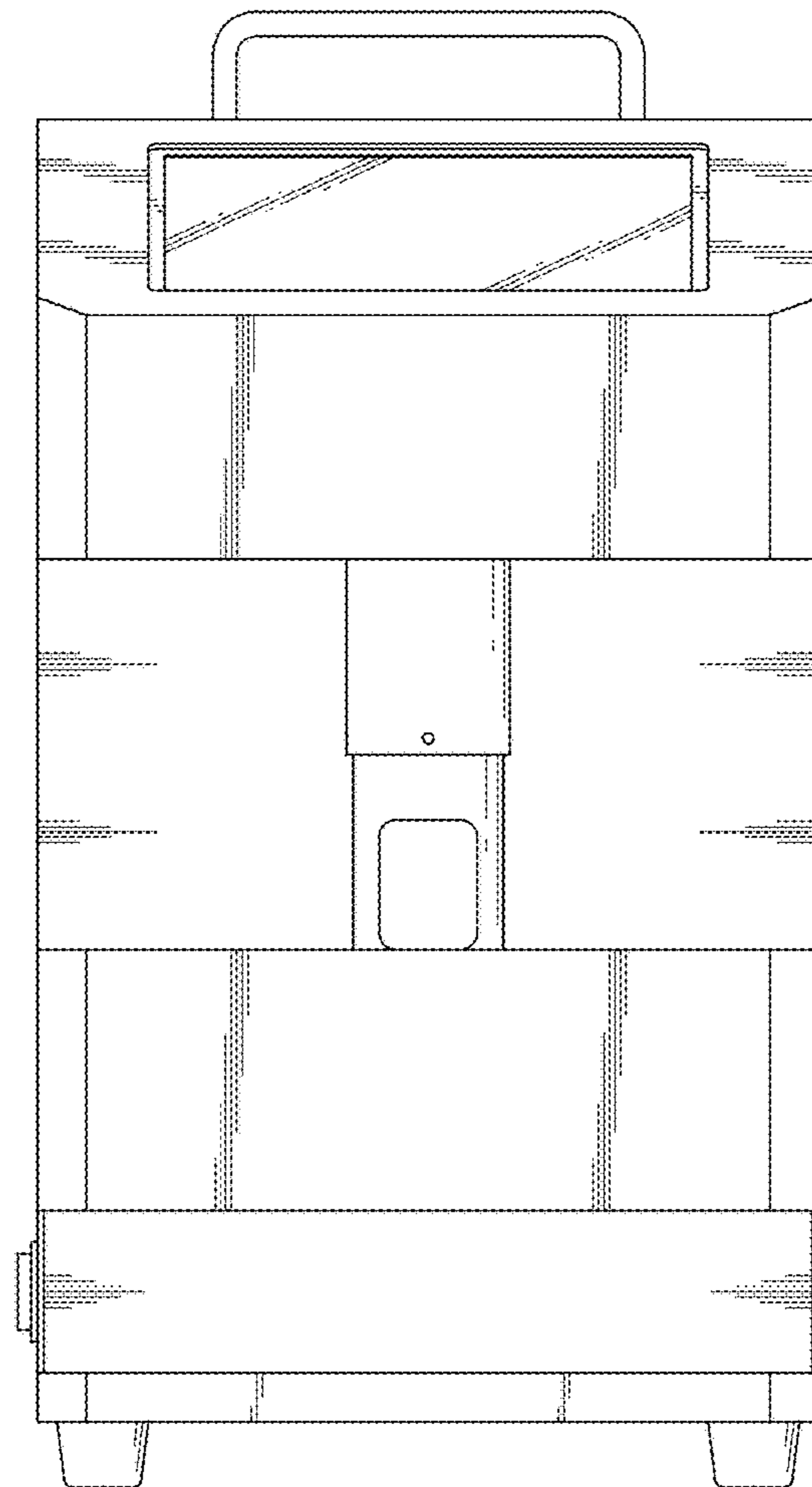


FIG. 2

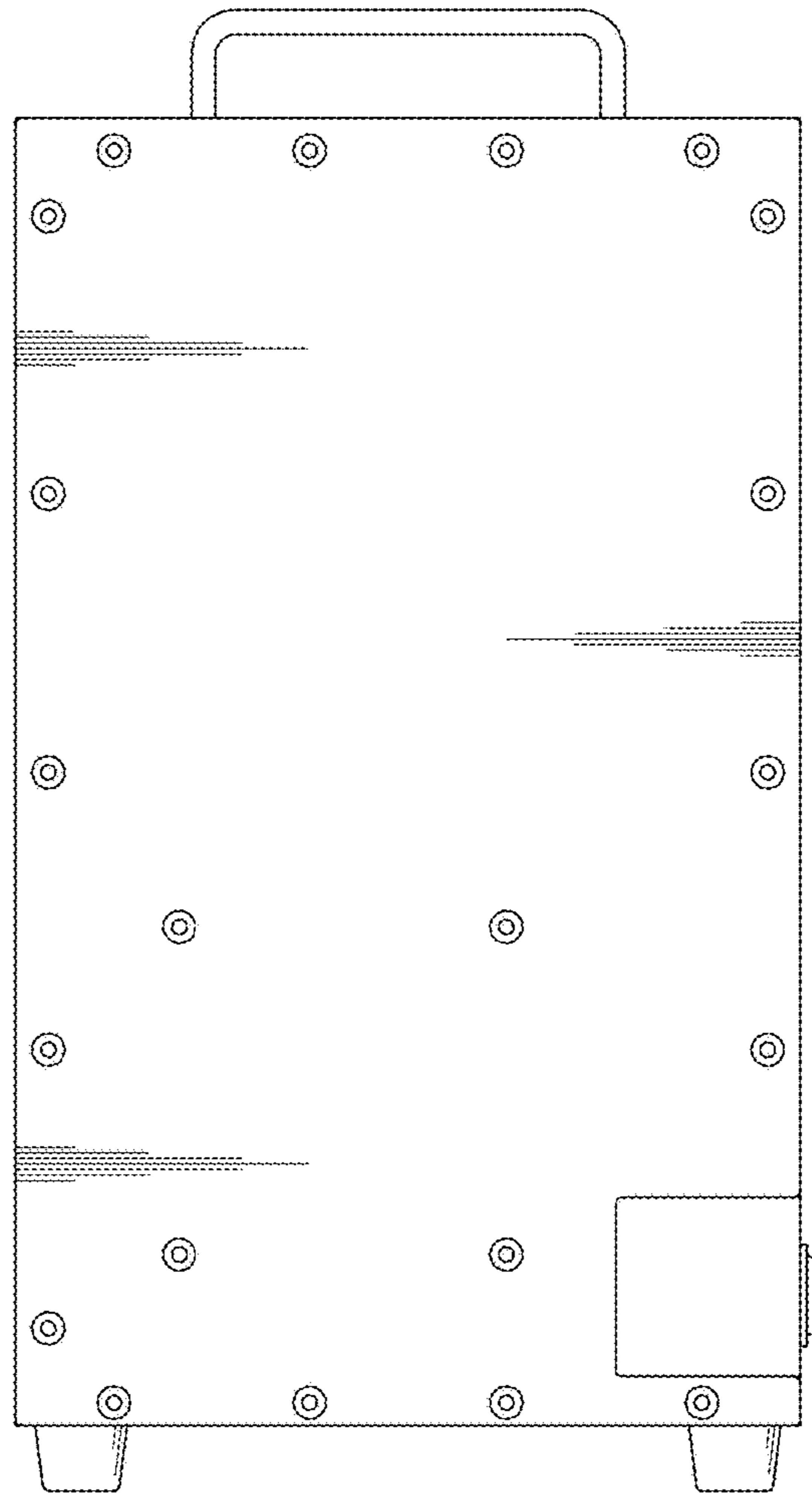


FIG. 3

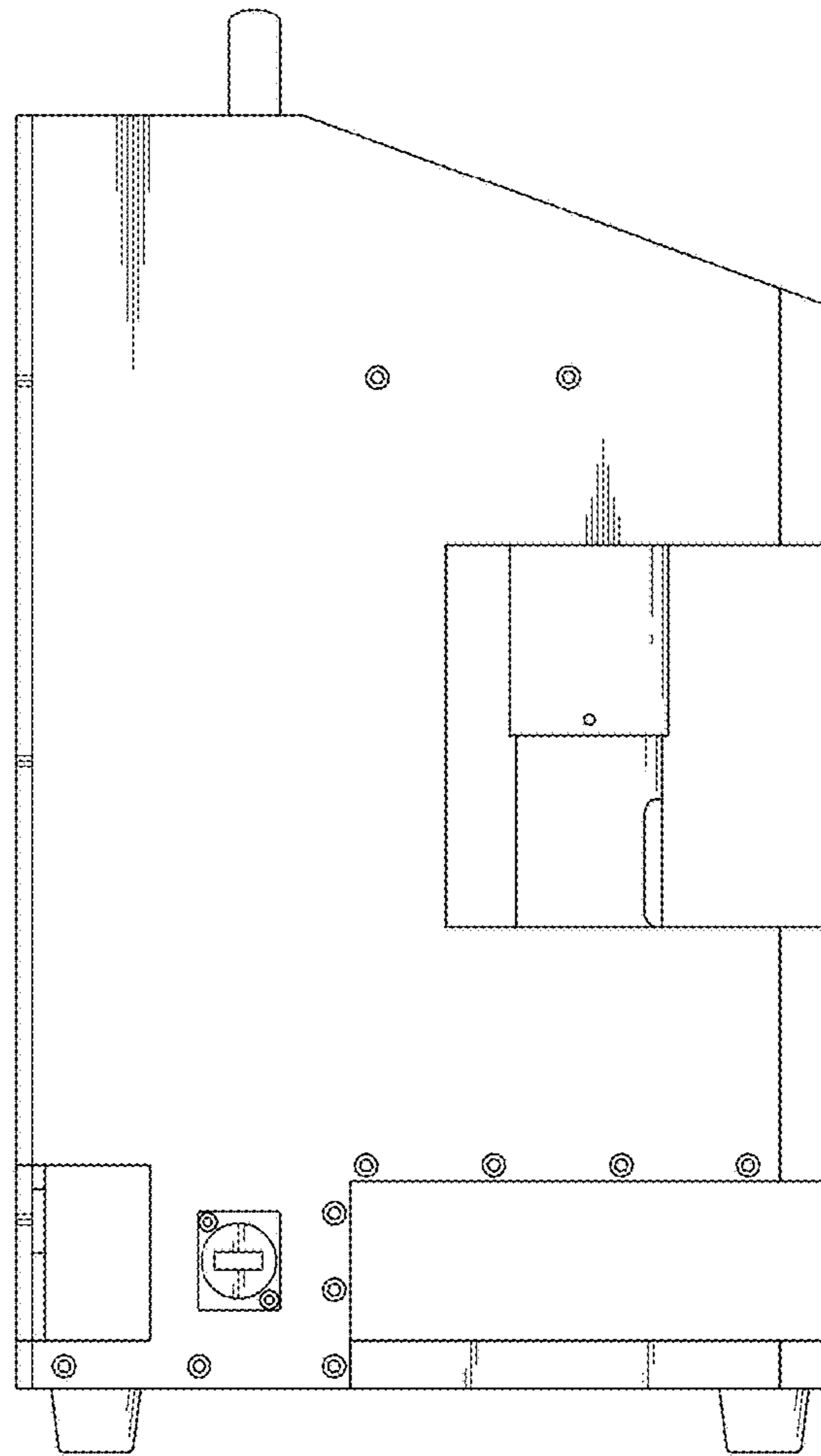


FIG. 4

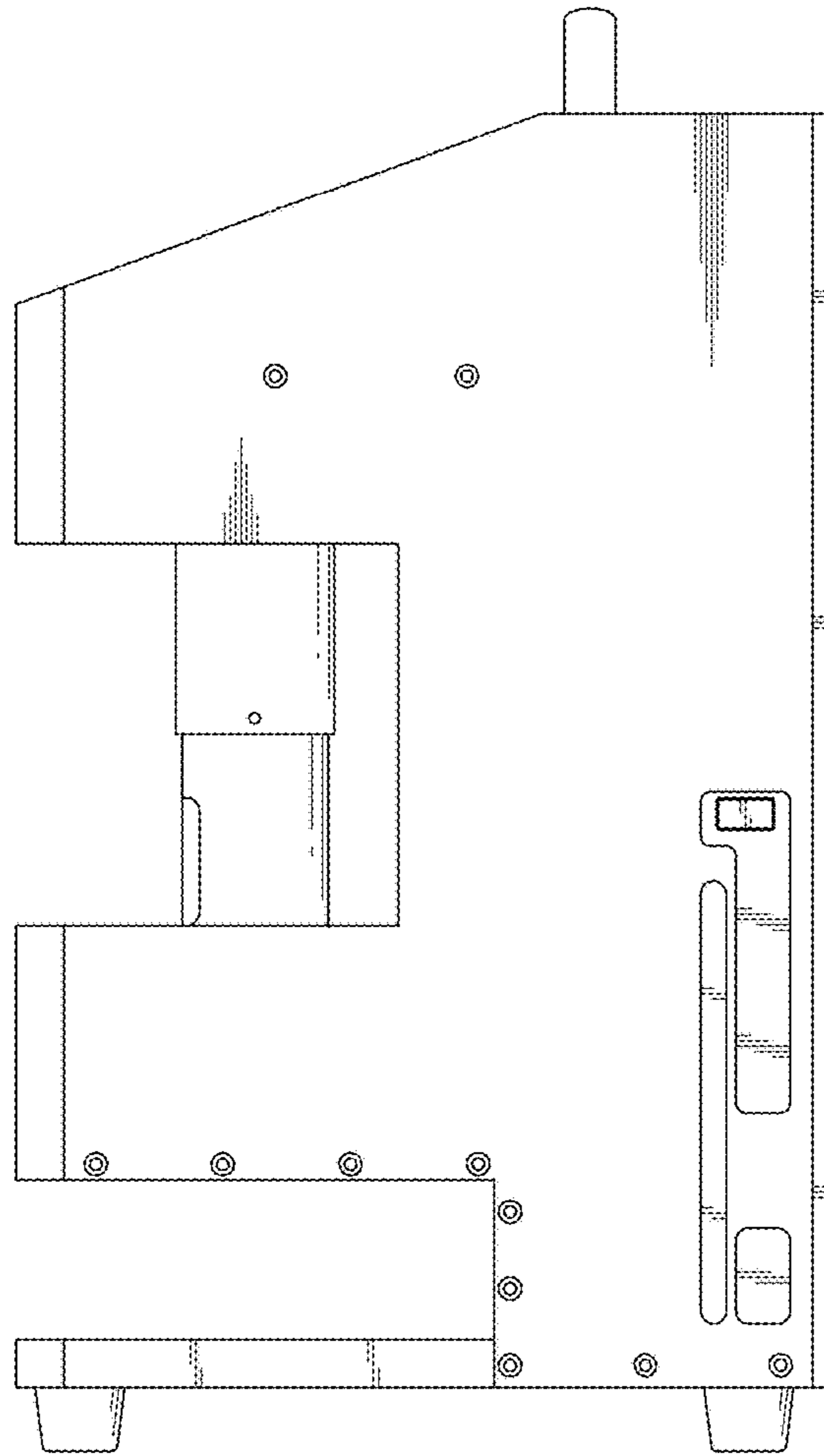


FIG. 5

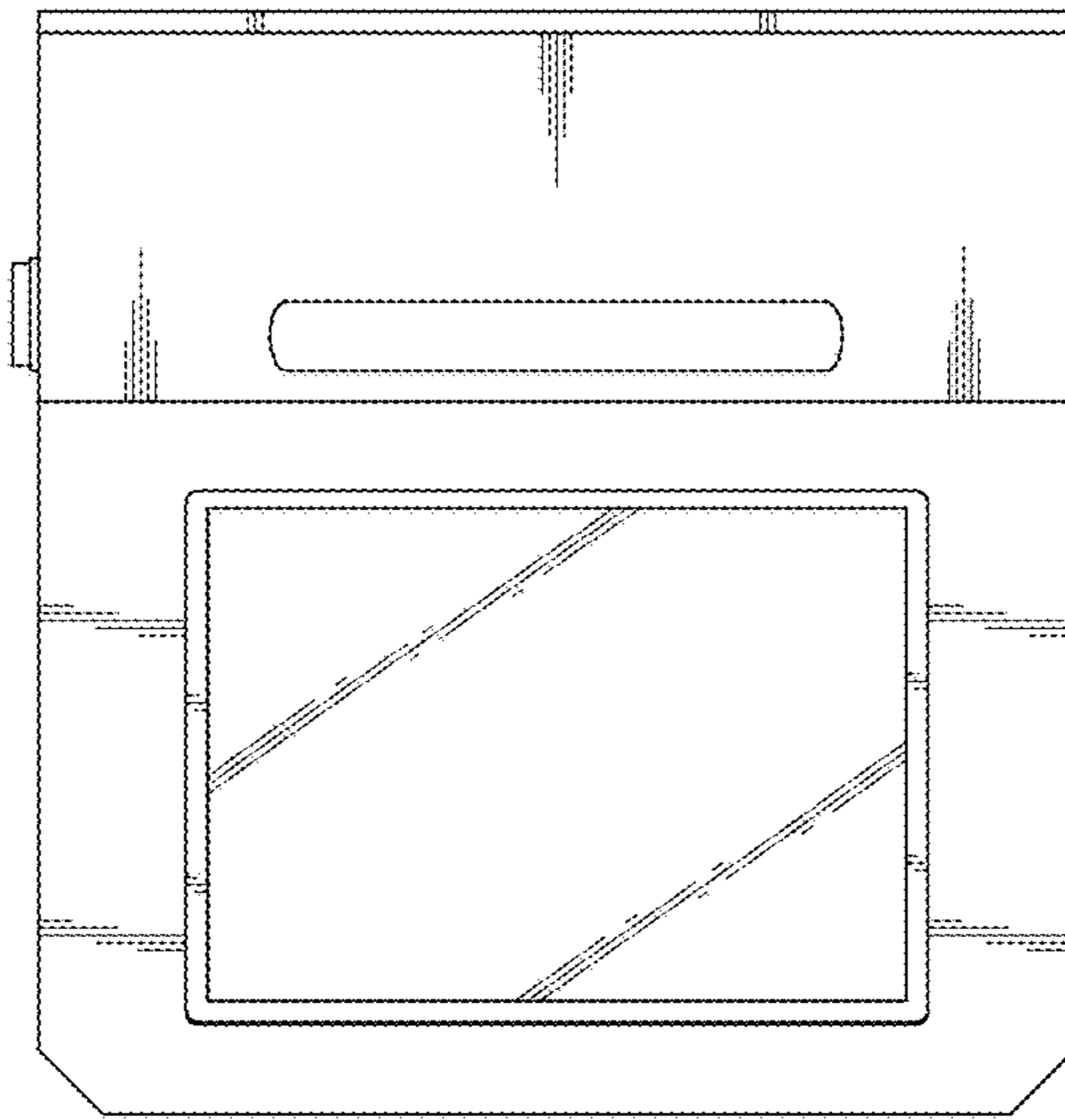


FIG. 6

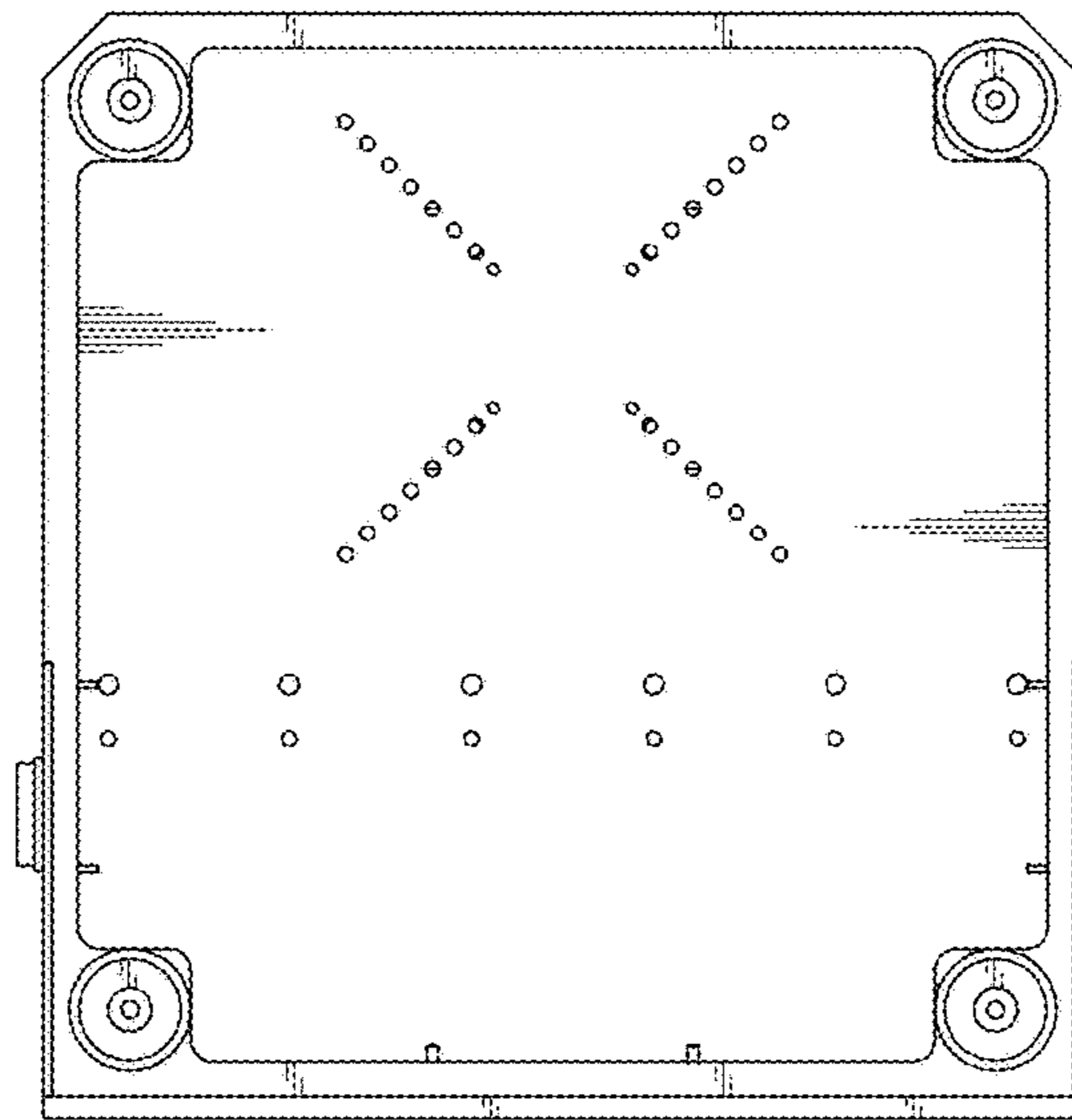


FIG. 7